Intelligent Automation of Diagnosis Process in Semiconductor Product Testing

NUS ISEM IE3100M Systems Design Project
NUS Supervisors: Prof. Andrew Lim, Dr. Li Chongshou
Industrial Supervisor: Mr. Hee Soon Kiet
Members: Katherine Erika, Lim Jia Hao, Meng Xiangwei, Nicholas Neo Hao Yang, Ren Yumeng

1. Background

- **Infineon Technologies:**
  - A world leader in semiconductor solutions
  - Asia Pacific headquarters located in Singapore

- **Product Test Engineering (PTE) Department:**
  - Final gate of defence in the entire semiconductor manufacturing process
  - Primarily responsible for the final testing of products

- **Semiconductor Manufacturing Process:**

- **Lot-on-Hold (LOH) Diagnosis:**
  - Lots are put on-hold temporarily if they fail any test
  - Product Engineers need to analyze the lots to decide on the root cause of test failure and subsequent action

2. Problem Drivers

3. Objectives

4. Methodology

5. Deliverables

6. User Acceptance Testing (UAT)

7. Achievement and Future Development

8. Conclusion

Skill-sets acquired in the System Design Project: